,	Se	ard	ch	No	ote	S
HII		18618	BIHIB	81181	11881	1818

|--|--|

Applicant(s)/Patent under Reexamination

10/766,183

Examiner

SEKI ET AL.
Art Unit

Wilson Lee

2163

	SEAR	CHED	
Class	Subclass	Date	Examiner
707	1-6, 9	3/18/2007	WL
			-
			•

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
707	1	3/18/2007	WL
707	3	3/18/2007	WL

(INCLUDING SEARCH STRATEGY) DATE EXMR				
	DATE			
EAST	3/18/2007	WL		
·				
•				
		-		
		<u> </u>		
	ļ			